

## LZ/LC/OL Package Bare Evaluation Board User Guide

### DESCRIPTION

Bare evaluation boards offer a method for evaluating Allegro current sensors in a lab environment. This document describes the use of the LC/LZ/OL Package Bare Evaluation Board. This evaluation board (ACSEVB-LC8-LZ6, TED-0004110) is intended for use with any LC, OL, or LZ package (custom 6-pin or 8-pin SOIC) Allegro Hall-based or TMR-based current sensors.

### FEATURES OF THE BARE BOARD

- Enhanced thermal performance
  - 6-layer PCB with 2 oz copper weight on all layers
  - Nonconductive-filled via-in-pad
  - High-performance FR4 material with 180°C glass transition temperature
- Flexible layout for user installed connection points
  - Standard Keystone test points
  - SMA/SMB connector
  - 2-pin headers
- Integrated current-loop resistance can be measured directly on the evaluation board after test-point installation; voltage drop can be measured for approximating power loss in the package.

### BARE EVALUATION BOARD CONTENTS

- **NOTE:** It is the responsibility of the user to assemble the board with the desired current sensor and supporting circuitry. This board does not come populated with an Allegro current sensor or other components.
- Recommended supporting circuitry for all compatible current sensors is listed in the Supporting Circuitry section.

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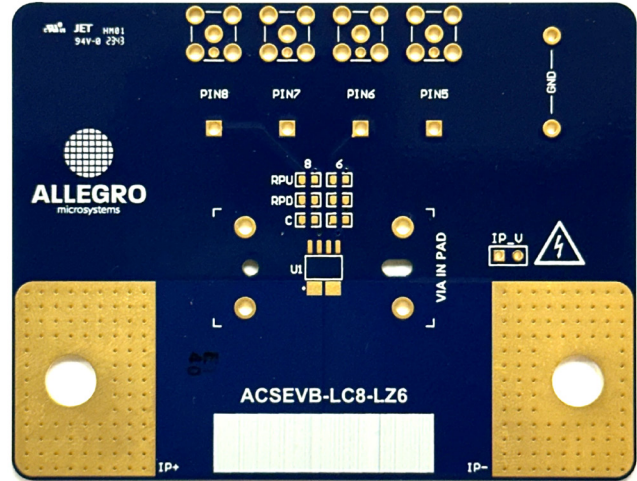


Figure 1: LZ/LC/OL Bare Evaluation Board

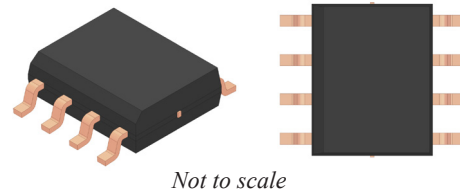


Figure 2: SOIC-8 (LC/OL Package)

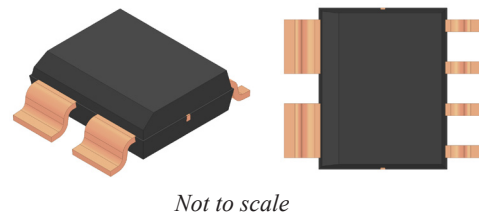


Figure 3: Custom 6-Pin Package (LZ Package)

## USING THE EVALUATION BOARD

### Evaluation Board Procedure

#### SETTING UP THE EVALUATION BOARD

Upon receiving the evaluation board, it is the responsibility of the user to populate the evaluation board with the desired Allegro current sensor. It is also the responsibility of the user to install test points, SMA/SMB connectors, header connectors, and supporting circuitry, as needed.

#### CONNECTING TO THE EVALUATION BOARD

The most reliable way to connect measurement instruments to the evaluation board is to use SMB/SMA or 2-pin header connectors along with coaxial cables. This configuration is the most resilient to external coupling, is the most mechanically stable, and is the preferred way to measure a high-speed signal.

Keystone test points provide a convenient way to connect any instrument but are recommended for DC setups only.

#### Evaluation Board Detailed Description

1. U1 is a combined LZ/LC/OL package footprint (pin 1 is on bottom left side of the package footprint; see the small white dot to the left of the package footprint).
2. U1 pins (5 to 8; see top and bottom view of evaluation board, EVB) allow the option to connect:
  - ◆ RPU: pull-up resistor to VCC
  - ◆ RPD: pull-down resistor to GND
  - ◆ C: decoupling or load capacitor to GND

NOTE: Even-numbered pin components are on the top layer of the evaluation board (6 and 8) and odd-numbered pin components are on the bottom layer of the board (5 and 7). All passive components are 0603 package size.

3. Optional through-hole test points (Keystone 5005 test points, e.g., Digikey# 36-5005-ND)
4. Optional standard SMB or SMA connection points (e.g., Digikey# 1868-1429-ND)
5. Optional 2-pin 100 mil header connector (note: either SMB or header can be assembled)
6. Primary current cables mounting positions (positive current flow direction is left to right)
7. Optional 2-pin 100 mil header connector for voltage drop measurement across the integrated current loop of the current sensor
8. RB1, RB2, RB3, and RB4: rubber bumper mounting positions (e.g., Digikey# SJ61A6-ND)

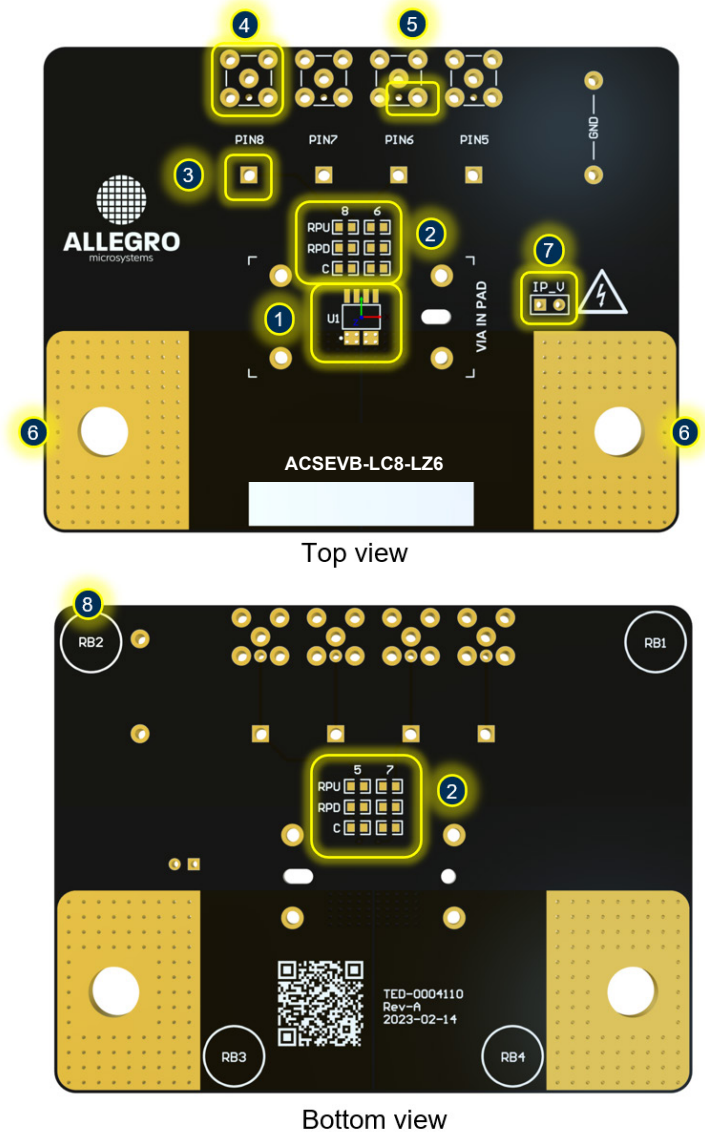


Figure 4: LZ/LC/OL Bare Evaluation Board Reference Image

## EVALUATION BOARD PERFORMANCE DATA

### Thermal Rise vs. Primary Current

Self-heating due to the flow of current in the package IP conductor should be considered during the design of any current sensing system. The sensor, printed circuit board (PCB), and contacts to the PCB generate heat and act like a heat sink when current moves through the system.

The thermal response is highly dependent on PCB layout, copper thickness, cooling techniques, and the profile of the injected current. The current profile includes peak current value, current on-time, and duty cycle.

Placing vias under the copper pads of the Allegro current sensor evaluation board minimizes the current path resistance and improves heat-sinking to the PCB, while vias outside of the pads limit the current path to the top of the PCB trace and have worse heat-sinking performance under the part (see Figure 5 and Figure 6). The ACSEVB-LC8-LZ6 includes vias in pad, which are recommended to improve thermal performance.

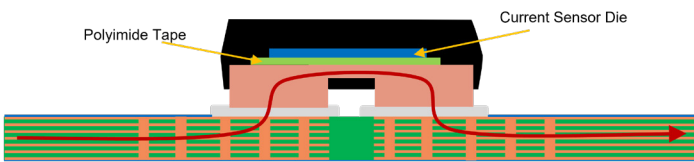


Figure 5: Vias Under Copper Pads

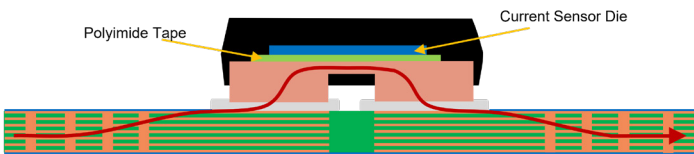


Figure 6: No Vias Under Copper Pads

The plot in Figure 7 shows the measured rise in steady-state die temperature of the LZ package versus DC continuous current at an ambient temperature,  $T_A$ , of 25°C for two board designs: filled vias under copper pads and no vias under copper pads.

The plot in Figure 8 shows the measured rise in steady-state die temperature of the LC package versus DC continuous current at an ambient temperature,  $T_A$ , of 25°C for two board designs: filled vias under copper pads and no vias under copper pads.

**Note: Using in-pad vias has better thermal performance than no in-pad vias, and this is the design the ACSEVB-LC8-LZ6 uses.**

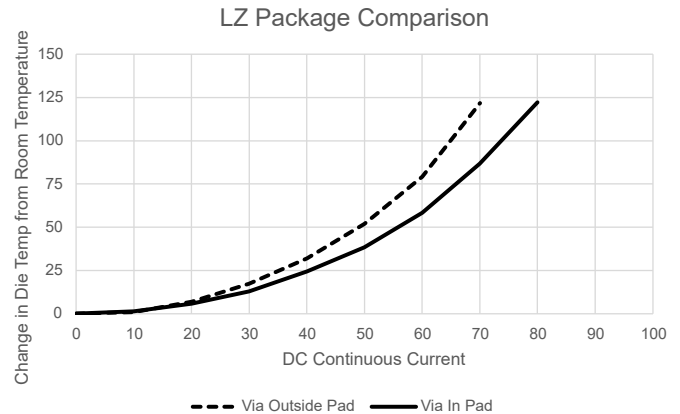


Figure 7: LZ Package Comparison with and without In-Pad Vias

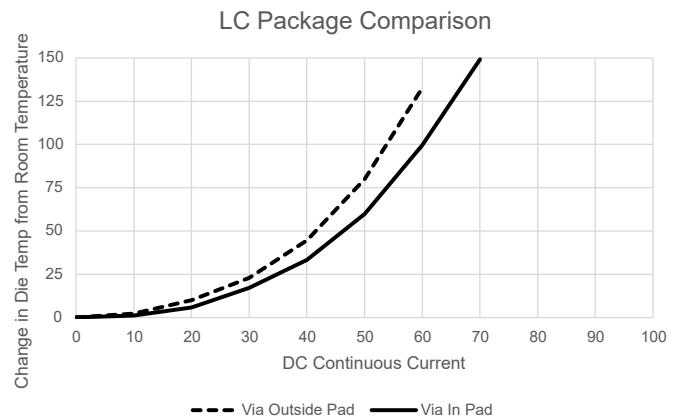


Figure 8: LC Package Comparison with and without In-Pad Vias

The thermal capacity of the LZ and LC packages should be verified by the end user in the application-specific conditions. The maximum junction temperature,  $T_{J(max)}$  (165°C), should not be exceeded. Measuring the temperature of the top of the package is a close approximation of the die temperature.

# SCHEMATIC

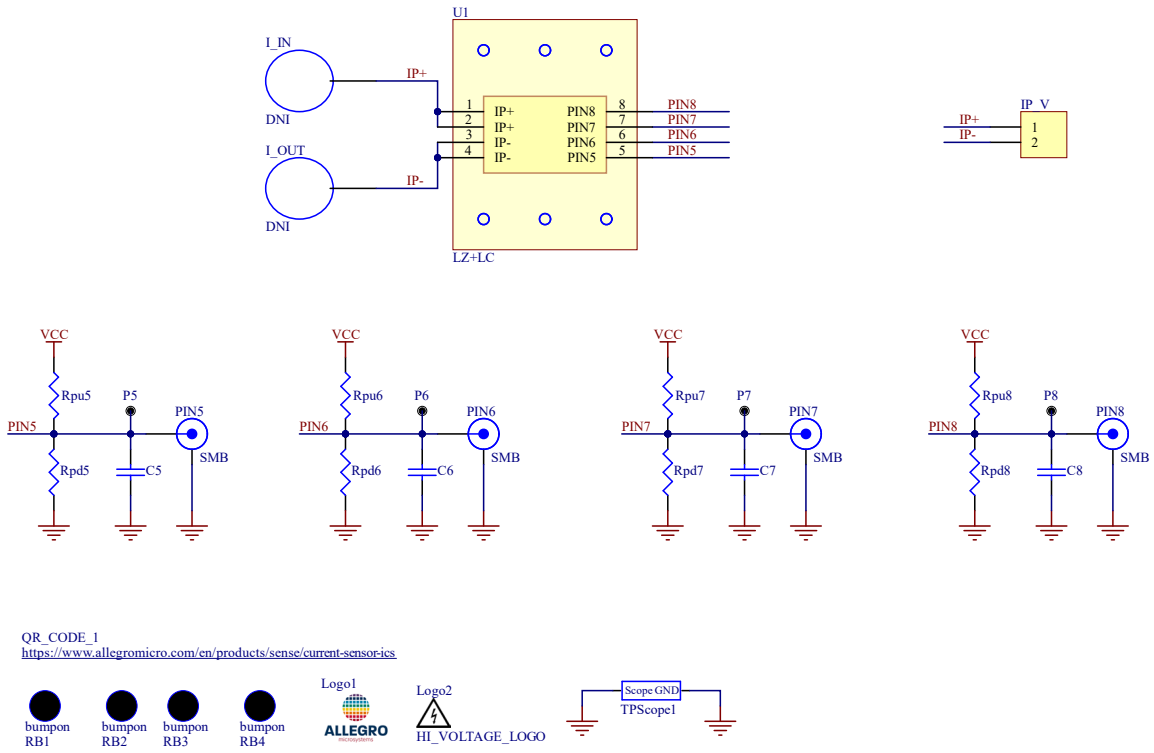


Figure 9: LZ/LC/OL Bare Evaluation Board Schematic

## LAYOUT

The LZ/LC/OL bare evaluation board has the option for a 2-pin 100 mil header connector, which allows the integrated current-loop resistance to be measured directly from the evaluation board. The voltage drop sensing is routed in the first internal layer (as not to reduce the isolation specification of the package). As a consequence, the voltage drop includes the parasitic resistance of the vias between the top layer and the first interior layer.

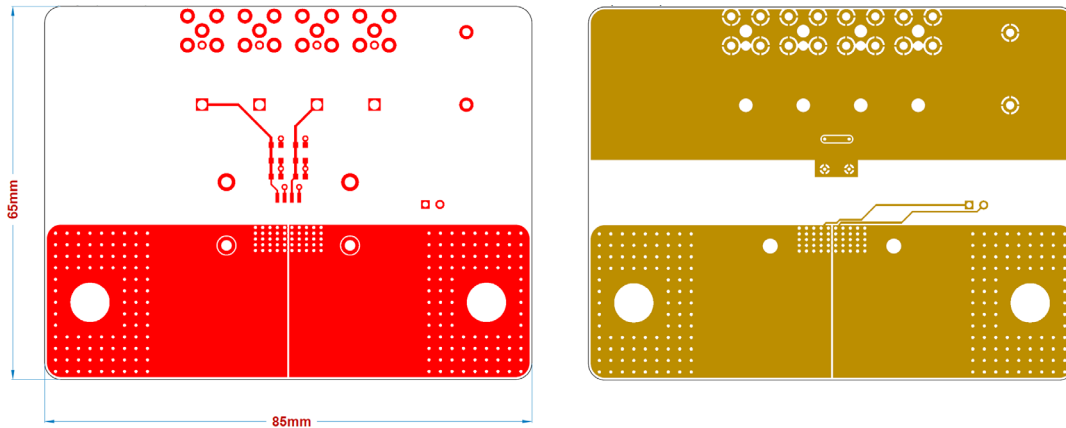


Figure 10: LZ/LC/OL Bare Evaluation Board Top Layer (left) and Interior Layer 1

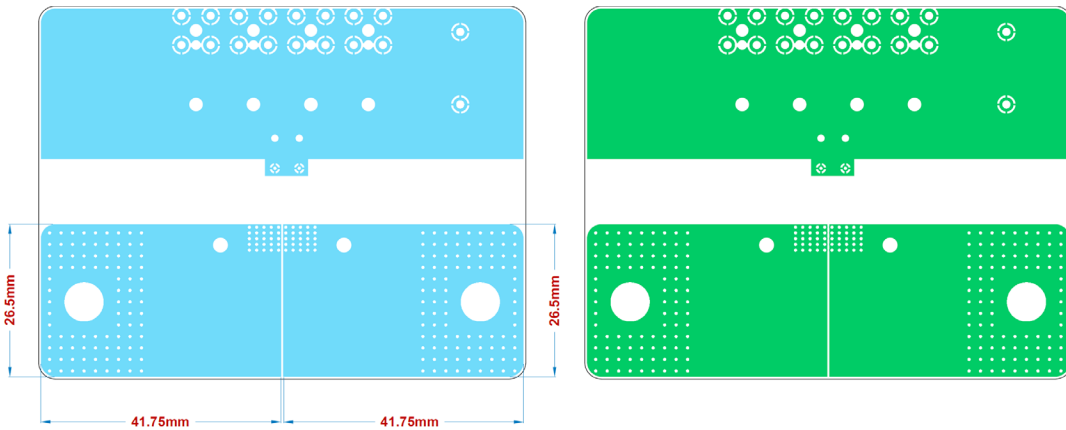


Figure 11: LZ/LC/OL Bare Evaluation Board Interior Layer 2 (left) and Interior Layer 3

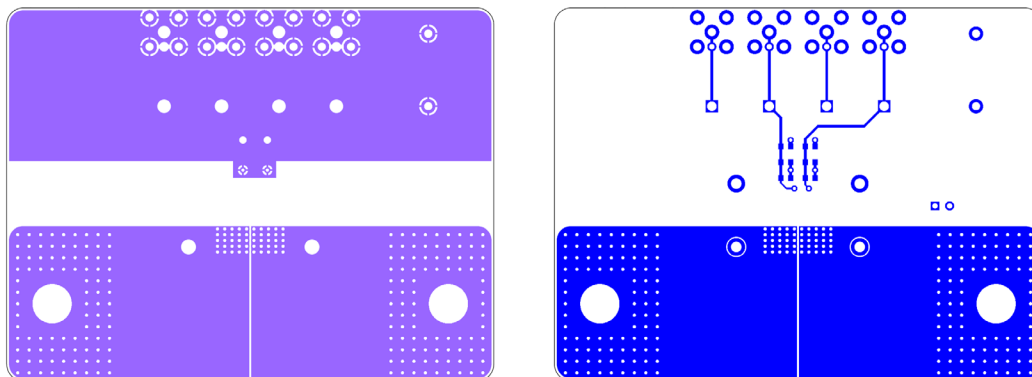


Figure 12: LZ/LC/OL Bare Evaluation Board Interior Layer 4 (left) and Bottom Layer

## SUPPORTING CIRCUITRY

Components listed are based on the typical application circuit given in the respective device datasheet. In the event of a conflict between this document and the main datasheet, the datasheet takes precedence.

**Table 1: Evaluation Board Circuitry**

### ACS37030/ACS37031 ASSEMBLY VARIANT

Pin	Terminal	Components
5	GND	Rpd5 = 0 $\Omega$
6	VREF	C6 = 1 nF, optional
7	VOUT	C7 = 1 nF, optional
8	VDD	C8 = 100 nF

### ACS37029/ACS37032 ASSEMBLY VARIANT

Pin	Terminal	Components
5	GND	Rpd5 = 0 $\Omega$
6	FAULT	Rpu6 = 10 k $\Omega$
7	VOUT	C7 = 1 nF, optional
8	VDD	C8 = 100 nF

### ACS37010 ASSEMBLY VARIANT

Pin	Terminal	Components
5	GND	Rpd5 = 0 $\Omega$
6	VREF	C6 = 1 nF, optional
7	VOUT	C7 = 1 nF, optional
8	VDD	C8 = 100 nF

### ACS37012 ASSEMBLY VARIANT

Pin	Terminal	Components
5	GND	Rpd5 = zero Ohm
6	FAULT	Rpu6 = 10k
7	VOUT	–
8	VDD	C8 = 100nF

### ACS71240 ASSEMBLY VARIANT

Pin	Terminal	Components
5	GND	Rpd5 = 0 $\Omega$
6	FAULT	Rpu6 = 10 k $\Omega$
7	VOUT	C7 = 1 nF, optional
8	VDD	C8 = 100 nF

### ACS724/ACS725 ASSEMBLY VARIANT

Pin	Terminal	Components
5	GND	Rpd5 = 0 $\Omega$
6	FILTER	C6 = 1 nF, optional
7	VOUT	C7 = 1 nF, optional
8	VDD	C8 = 100 nF

## RELATED LINKS AND APPLICATION SUPPORT

**Table 2: Related Documentation and Application Support**

Documentation	Summary	Location
Allegro Current Sensors Webpage	Product datasheet defining common electrical characteristics and performance characteristics	<a href="https://www.allegromicro.com/en/products/sense/current-sensor-ics">https://www.allegromicro.com/en/products/sense/current-sensor-ics</a>
Allegro Current Sensor Package Documentation	Schematic files, step files, package images	<a href="https://www.allegromicro.com/en/design-support/packaging">https://www.allegromicro.com/en/design-support/packaging</a>
An Effective Method for Characterizing System Bandwidth in Complex Current Sensor Applications	Application note describing methods used by Allegro to measure and quantify system bandwidth	<a href="https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/an-effective-method-for-characterizing-system-bandwidth-an296169">https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/an-effective-method-for-characterizing-system-bandwidth-an296169</a>
DC and Transient Current Capability/Fuse Characteristics of Surface Mount Current Sensor ICs	DC and Transient Current Capability/Fuse Characteristics of Surface Mount Current Sensor ICs	<a href="https://www.allegromicro.com/en/Insights-and-Innovations/Technical-Documents/Hall-Effect-Sensor-IC-Publications/DC-and-Transient-Current-Capability-Fuse-Characteristics.aspx">https://www.allegromicro.com/en/Insights-and-Innovations/Technical-Documents/Hall-Effect-Sensor-IC-Publications/DC-and-Transient-Current-Capability-Fuse-Characteristics.aspx</a>
High-Current Measurement with Allegro Current Sensor IC and Ferromagnetic Core: Impact of Eddy Currents	Application note focusing on the effects of alternating current on current measurement	<a href="https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/an296162_a1367_current-sensor-eddy-current-core">https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/an296162_a1367_current-sensor-eddy-current-core</a>
Secrets of Measuring Currents Above 50 Amps	Application note regarding current measurement greater than 50 A	<a href="https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/an296141-secrets-of-measuring-currents-above-50-amps">https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/an296141-secrets-of-measuring-currents-above-50-amps</a>
Allegro Hall-Effect Sensor ICs	Application note describing Hall-effect principles	<a href="https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/allegro-hall-effect-sensor-ics">https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/allegro-hall-effect-sensor-ics</a>
Hall-Effect Current Sensing in Electric and Hybrid Vehicles	Application note providing a greater understanding of hybrid electric vehicles and the contribution of Hall-effect sensing technology	<a href="https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/hall-effect-current-sensing-in-electric-and-hybrid-vehicles">https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/hall-effect-current-sensing-in-electric-and-hybrid-vehicles</a>
Hall-Effect Current Sensing in Hybrid Electric Vehicle (HEV) Applications	Application note providing a greater understanding of hybrid electric vehicles and the contribution of Hall-effect sensing technology	<a href="https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/hall-effect-current-sensing-in-hybrid-electric-vehicle-hev-applications">https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/hall-effect-current-sensing-in-hybrid-electric-vehicle-hev-applications</a>
Achieving Closed-Loop Accuracy in Open-Loop Current Sensors	Application note regarding current sensor IC solutions that achieve near closed-loop accuracy using open-loop topology	<a href="https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/achieving-closed-loop-accuracy-in-open-loop-current-sensors">https://allegromicro.com/en/insights-and-innovations/technical-documents/hall-effect-sensor-ic-publications/achieving-closed-loop-accuracy-in-open-loop-current-sensors</a>
Allegro Current Sensor ICs Can Take the Heat! Unique Packaging Options for Every Thermal Budget	Application note regarding current sensors and package selection based on thermal capabilities	<a href="https://allegromicro.com/-/media/files/application-notes/an296190-current-sensor-thermals.pdf">https://allegromicro.com/-/media/files/application-notes/an296190-current-sensor-thermals.pdf</a>
Explanation Of Error Specifications For Allegro Linear Hall-Effect-Based Current Sensor Ics And Techniques For Calculating Total System Error	Application note describing error sources and their effect on the current sensor output	<a href="https://allegromicro.com/-/media/files/application-notes/an296181-accs72981-error-calculation.pdf">https://allegromicro.com/-/media/files/application-notes/an296181-accs72981-error-calculation.pdf</a>

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## Revision History

Number	Date	Description
–	March 23, 2023	Initial release
1	January 5, 2024	Minor editorial updates
2	April 16, 2024	Corrected typos in part numbers (pages 1 and 3) and made minor editorial updates throughout.
3	August 21, 2024	Updated title and description (page 1), minor editorial updates throughout

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